Advancing
Materials Characterization

Lake Shore offers precision platforms for materials research

THz Material Characterization System

A non-contact measurement system that uses THz-frequency energy to measure across a wide range of frequencies, temperatures, and field strengths

Ideal for: semiconductor materials • complex oxide systems • thin films • superconducting metamaterials • 2D materials

Hall Effect Measurement Systems

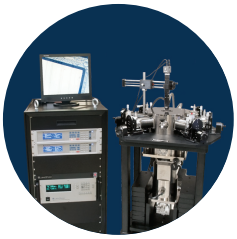
Robust hardware/software systems for performing DC field Hall measurements with options for AC field Hall, high or low resistances, and variable temperature

Ideal for: ZnO & other transparent conducting oxides • metal oxides • III-V, II-VI, & elemental semiconductors • complex oxide systems

VSMs/AGMs

High-sensitivity electromagnet-based systems for accurately characterizing magnetic materials over a wide range of temperatures and fields to >3 T

Ideal for: magnetic thin films & multi-layers • magnetic nanomaterials • permanent magnets, including rare earth materials • MCE materials



Cryogenic Probe Stations

Micro-manipulated stations for non-destructive on-wafer probing and measurement of materials in a tightly controlled environment

Ideal for: transition metal dichalcogenide & 2D material transistors • CNT & nanowire devices • GaN & other wide-bandgap devices • MEMs

Lake Shore CRYOTRONICS

ADVANCING SCIENCE

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H																	He
Li	Be											B	C	N	O	F	Ne
Na	Mg											Al	Si	P	S	Cl	Ar
K	Ca	Sc	Ti	V	Cr	Mn	Fe	Co	Ni	Cu	Zn	Ga	Ge	As	Se	Br	Kr
Rb	Sr	Y	Zr	Nb	Mo	Tc	Ru	Rh	Pd	Ag	Cd	In	Sn	Sb	Te	I	Xe
Cs	Ba	La	Hf	Ta	W	Re	Os	Ir	Pt	Au	Hg	Tl	Pb	Bi	Po	At	Rn
Fr	Ra	Ac	Rf	Db	Sg	Bh	Hs	Mt	Ds	Rg	Cn	Uut	Fl	Uup	Lv	Uus	Uuo

Ce	Pr	Nd	Pm	Sm	Eu	Gd	Tb	Dy	Ho	Er	Tm	Yb	Lu
Th	Pa	U	Np	Pu	Am	Cm	Bk	Cf	Es	Fm	Md	No	Lr

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